



412th Test Wing



War-Winning Capabilities ... On Time, On Cost



Title: Parametric TLE

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Preamble:

- Applying parametric survival models to analyze target location error (TLE) was the brainchild of Todd Remund, Greg Hutto, and Jeff Beekman (Beekster).
- This presentation details how the parametric survival model was adapted to TLE.
- An example is given- input file and source code in Python are available



Introduction



- Basic idea: precision target location, germane to navigation, weapon delivery and target tracking, can be related to distance from a target, as well as other possible explanatory factors (elevation and azimuth angles to the target, for example)
- Use the approach presented in Meeker and Escobar, *Statistical Reliability*, to use a generalized linear model based on log-link distribution function.
- Model fitting capabilities exist in JMP, as well as code written in Python and R



CEP



- CEP, CE10 and CE90 defined as
 - radius of a circle about the target that has the property that 50%, 10%, or 90% (respectively) of the values are within a circle of radius 'CEP' and so forth
- Using parametric survival model, estimate CEP (or CE90, CE10) as functions of range R and associated covariates
- Additionally, we'd like confidence intervals for CE estimates, an RMS error estimate and 95/90 tolerance limits



Development



- TLE error estimates are similar to reliability of a component;
 - The cumulative probability of failure can be related to time in service
 - Similarly, cumulative probability of TLE can be related to range to the target
- Reliability (parametric) modeling provides a way to specify CEP (or CEwhatever) as a function of range to target.



Parametric Model

- Summary: generalized linear model
- $P(T \leq t_i | \mathbf{X}) = \Phi\left(\frac{\log(t_i) - \mu_i}{\sigma_i}\right)$, where
 $\mu_i = b_0 + b_1 \mathbf{X}_i$ and $\sigma_i = b_2 + b_3 \mathbf{X}_i$
- Percentile estimates, RMS, tolerance intervals all given by Φ
- \mathbf{X} an $n \times m$ design matrix, columns contain covariates
- Details in Meeker and Escobar, *Statistical Reliability*



A few details



- \mathbf{X} , design matrix, has n rows, m columns, $X(i,j)$ = i -th observation, explanatory variable j
- In terms of matrix algebra:
 - $\boldsymbol{\mu} = \mathbf{X}\boldsymbol{\beta} + \boldsymbol{\epsilon}$,
 $\boldsymbol{\mu}$ is $n \times 1$, \mathbf{X} is $n \times m$, $\boldsymbol{\beta}$ is $m \times 1$, and $\boldsymbol{\epsilon}$ is $n \times 1$
(similarly for $\boldsymbol{\sigma}$)
- Estimates of $\boldsymbol{\beta}$ found by maximum likelihood
- Log link functions:

Log Error	Link Distribution
Log normal	normal
Extreme value	Weibull
log-logistic	logistic



Link Equations

- The key is the link between the distribution of the log of a random variable and the distribution of the random variable;
 - $Y \sim$ Weibull, then $\log(Y) \sim$ gumbel (EVS)
 - $Y \sim$ Normal, then $\log(Y) \sim$ lognormal
 - $Y \sim$ Logistic, then $\log(Y) \sim$ loglogistic
- Fit a generalized linear model to the $\log(Y)$ - in the 'normal' case:

$$P(\log(Y) < y) = \Phi_{\ln}^{-1} \left(\frac{y - \mu_r}{\sigma_r} \right),$$

μ_r , and σ_r functions of covariates-



Estimation

- Estimation of parameters, β_0 , β_1 , and σ is based on the likelihood function

$$\text{likelihood}(\beta_0, \beta_1, \sigma) = \prod_{i=1}^n \frac{1}{\sigma} \phi\left(\frac{y_i - \mu_i}{\sigma}\right)$$

- $\mu_i = \beta_0 + \beta_1 X_i$ and $\sigma_i = \beta_2 + \beta_3 X_i$
- Maximum likelihood estimates of β 's



Normal-lognormal case

For Φ_{\ln} , the log normal distribution function,

$$\Pr(Y \leq y) = F(y; \mu, \sigma) = F(y; \beta_0, \beta_1, \sigma) = \Phi_{\ln}((y - \mu) / \sigma)$$

The quantile function for this model is

$$y_p(r) = \mu + \Phi_{\ln}^{-1}(p)\sigma = \beta_0 + \beta_1 r + \Phi_{\ln}^{-1}(p)\sigma$$

The quantile function then gives us probability curves for TLE, just select 'p'



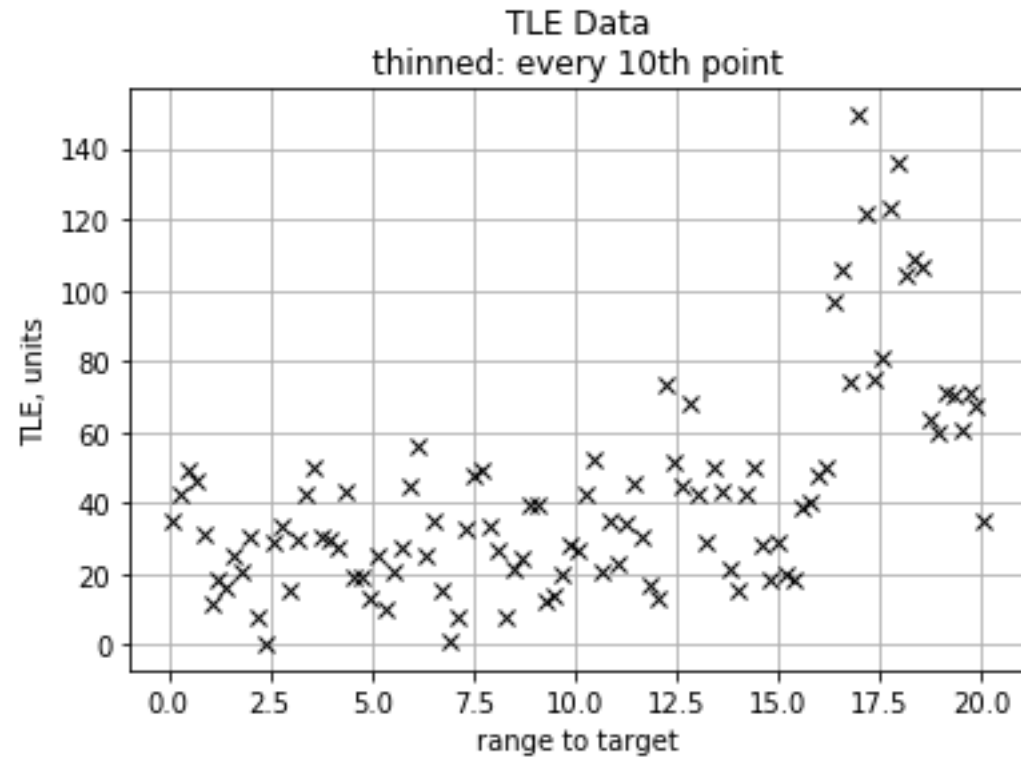
Upshot..



- Parametric modeling, if appropriate may avoid the effort to get IID errors
- Drawback- modeling assumes each realization (data run) is representative of a stationary, ergodic process
- Better approach may be a hierarchical model

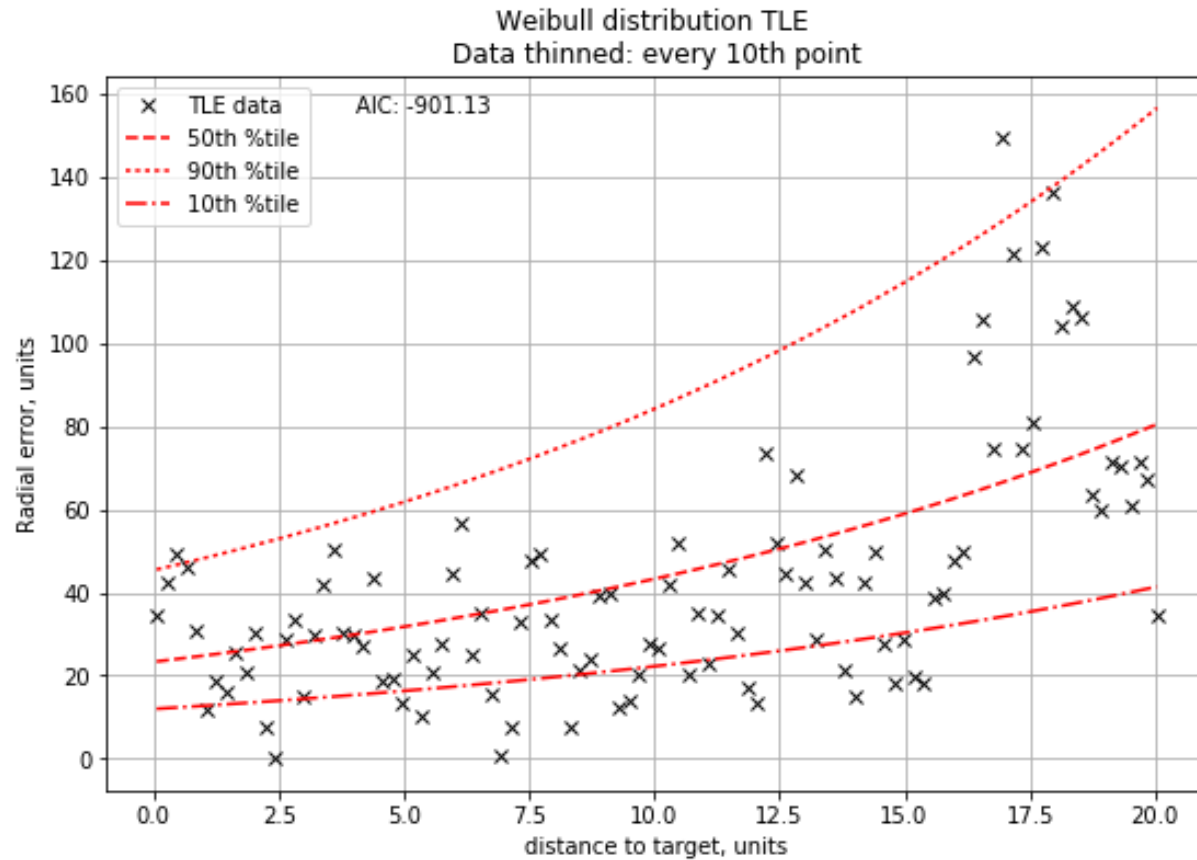


Example: Original data





Weibull distribution





Questions??

